

UNITED STATES PATENT AND TRADEMARK OFFICE
CERTIFICATE OF CORRECTION

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PATENT NO. : 5,440,920
DATED : August 15, 1995
INVENTOR(S) : Pan S. Jung, Daphna R. Yaniv

It is certified that error appears in the above-identified patent and that said Letters Patent is hereby corrected as shown below:

Replace "L.A. Nagahara, 'Preparation and Characterization of STM Tips for Electrochemical Studies'." with --L.A. Nagahara, "Preparation and Characterization of STM Tips for Electrochemical Studies", Rev. Sci. Instrum. 60(10), pp. 3128-3130, October 1989.--

Replace "Jung et al., 'Novel Stationary-Sample Atomic Force Microscope with Beam-Tracking Lens', *Electronic Letters*, vol. 19 No. 3, 14 Dec. 1992, pp. 264-265." with --Jung et al., "Novel Stationary-Sample Atomic Force Microscope with Beam-Tracking Lens", *Electronic Letters*, vol. 19 No. 3, 4 Feb. 1993, pp. 264-265.--

Signed and Sealed this
Thirtieth Day of July, 1996

Attest:



BRUCE LEHMAN

Attesting Officer

Commissioner of Patents and Trademarks